Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination YOSHINO ET AL.	
10/539,109		
Examiner	Art Unit	
Quang T. Van	3742	

SEARCHED					
Class	Subclass	Date	Examiner		
219	756,750	7/19/06	av		
	710,748		١ ،		
	746.751	7/19/06			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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